

Search Notes

Application/Control No.

10/661,824

Examiner

Yixing Qin

Applicant(s)/Patent under
Reexamination

CHIZAWA ET AL.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Performed text searching for detection of abnormalities on substrates	12/26/2007	YQ